

**ABSTRACT OF THE DISCLOSURE****I/O STRESS TEST**

The present invention provides a method, computer program product, input/output device, and computer system for stress testing the I/O subsystem of a computer system. An input/output device capable of engaging in repetitive direct memory access (DMA) transfers with pseudo-randomized transfer parameters is allowed to execute multiple DMA transfers with varying parameters.

5 In this way, a single type of device may be used to simulate the effects of multiple types of devices. Multiple copies of the same I/O device may be used concurrently in a single computer system along with processor software to access the same portions of memory.

10 15 In this way, false sharing, true sharing may be effected.